

Representing gate-level SET faults by multiple SEU faults on RT-level

Bagbaba, Ahmet Cagri; Jenihhin, Maksim; Ubar, Raimund-Johannes; Sauer, Christian 2020 IEEE 26th International Symposium on On-Line Testing and Robust System Design (IOLTS), 13-15 July 2020 : proceedings 2020 / art. 19889351, 6 p. : ill
<https://doi.org/10.1109/IOLTS50870.2020.9159715>